

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/309,766	Fujimura et al	
<b>PTO 892</b>		Examiner	Art Unit	Page 1 of 1
		Kenneth J. Ramsey	2879	

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
A	US-5,697,825-A	12-1997	Dynka et al	445	25
B					
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D					
E					
F					
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H					
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**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
P						
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Art Unit: 2879

<b>Notice of References Cited</b>		Application/Control No. 09/309,766	Applicant(s)/Patent Under Reexamination Fujimura et al	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	X	**A full Translation of Banno et al was submitted by applicants on 1/20/02
	Y	
	Z	

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